

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Not for submission under 37 CFR 1.99)	Application Number		10520647	
	Filing Date		2008-08-13	
	First Named Inventor	Marie D'Angelo		
	Art Unit	2822		
	Examiner Name	Chiu, TSZ K.		
Attorney Docket Number		034299-617		

U.S.PATENTS						
Examiner Initial*	Cite No	Patent Number	Kind Code ¹	Issue Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear
	1	7008886	B2	2006-03-07	Derycke et al.	

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	1	20030102490	A1	2003-06-05	Kubo et al.	
	2	20040101625	A1	2004-05-27	Das et al.	
	3	20040104406	A1	2004-06-03	Derycke et al.	
	4	20050084639	A1	2005-03-24	Hisada et al.	

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1	0703626	EP	1996-03-27			<input type="checkbox"/>
2	2823770	EP	2002-10-25			<input type="checkbox"/>
3	0139257	WO	2001-05-31			<input type="checkbox"/>
4	02085778	WO	2002-10-31			<input type="checkbox"/>
5	02086202	WO	2002-10-31			<input type="checkbox"/>
6	2006005869	WO	2006-01-19			<input type="checkbox"/>
7	2007003576	WO	2007-01-11			<input type="checkbox"/>
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1	Amy, F. "Oxynitridation of Cubic Silicon Carbide (100) Surfaces," J. Vac. Sci. Technol. A. 17(5), Sep/Oct 1999, pp. 2629-2633.	<input type="checkbox"/>
2	Aristov, V. Yu et al., "High Temperature Dismantling of Si Atomic Lines on β -SiC (100)," Surface Science 440, 1999, pp. L825-L830.	<input type="checkbox"/>
3	Bandyopadhyay, S. et al., "Computational Paradigm for Nanoelectronics: Self-Assembled Quantum Dot Cellular Neural Networks," IEE Procs-Circuits Devices Syst., Vol. 152, No. 2, April 2005, pp. 85-92.	<input type="checkbox"/>
4	Derycke, V. et al., "Nanochemistry at the Atomic Scale Revealed in Hydrogen-Induced Semiconductor Surface Metallization," Nature Materials, Vol. 2, April 2003, pp. 253-258.	<input type="checkbox"/>
5	Esaki, L. "New Phenomenon in Narrow Germanium p-n Junctions," Letters to the Editor, 2007, pp. 603-604.	<input type="checkbox"/>
6	Ganem, J.-J. et al., "NRA and XPS Characterizations of Layers Formed by Rapid Thermal Nitridation of Their SiO ₂ films," Nuclear Instruments and Methods in Physics Research B64 (1992), pp. 744-749.	<input type="checkbox"/>
7	Haraguchi, K. et al., "GaAs p-n Junction Formed in Quantum Wire Crystals," Appl. Phys. Lett. 60 (6), February 1992, pp. 745-747.	<input type="checkbox"/>
8	International Preliminary Examination Search Report, PCT/FR2005/050469, 2 pgs. February 11, 2005.	<input type="checkbox"/>
9	Lyo, In-Whan et al., "Negative Differential Resistance on the Atomic Scale: Implications for Atomic Scale Devices," September 1989, pp. 1369-1371.	<input type="checkbox"/>
10	Semond, F. et al., "Direct SiO ₂ / β -SiC(100)3x2 Interface Formation from 25 °C to 500 °C," Appl. Phys. Lett. 68 (15), April 1996, pp. 2144-2146.	<input type="checkbox"/>
11	Soukiasian, P. et al., "Highly Stable Si Atomic Line Formation on the β -SiC(100) Surface," Physical Review Letters, Volume 79, Number 13, September 1997, pp. 2498-2501.	<input type="checkbox"/>

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12	Soukiasian P. et al. "Atomic Scale Control and Understanding of Cubic Silicon Carbide Surface Reconstructions, Nanostructures and Nanochemistry" Journal of Physics: Condensed Matter IOP Publishing UK, Vol. 16, No. 17, May 2004, pp. S1611-S1658.	<input type="checkbox"/>
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